



SLOVENSKI STANDARD

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Nadomešča:

SIST EN 60444-8:2004

Merjenje parametrov kvarčnih kristalov - 8. del: Preskusna pritrditev za enoto kvarčnih kristalov za površinsko montažo (IEC 60444-8:2016)

Measurement of quartz crystal unit parameters - Part 8 : Test fixture for surface mounted quartz crystal units (IEC 60444-8:2016)

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Piezoelectric devices

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EUROPEAN STANDARD

EN 60444-8

NORME EUROPÉENNE

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April 2017

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English Version

Measurement of quartz crystal unit parameters -
Part 8 : Test fixture for surface mounted quartz crystal units
(IEC 60444-8:2016)

Mesure des paramètres des résonateurs à quartz -
Partie 8: Dispositif d'essai pour les résonateurs
à quartz montés en surface
(IEC 60444-8:2016)

Messung von Schwingquarz-Parametern -
Teil 8: Prüfaufbau für oberflächenmontierbare
Schwingquarze
(IEC 60444-8:2016)

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This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

[SIST EN 60444-8:2017](#)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

EN 60444-8:2017**European foreword**

The text of document 49/1126/CDV, future edition 2 of IEC 60444-8, prepared by IEC/TC 49 "Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 60444-8:2017.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2017-10-19
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2020-01-19

This document supersedes EN 60444-8:2003.

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Endorsement notice

The text of the International Standard IEC 60444-8:2016 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60122-1	NOTE	Harmonized as EN 60122-1.
IEC 60444-1:1986	NOTE	Harmonized as EN 60444-1:1997 (not modified).
IEC 60444-2	NOTE	Harmonized as EN 60444-2.
IEC 60444-6	NOTE	Harmonized as EN 60444-6.
IEC 60444-7	NOTE	Harmonized as EN 60444-7.
IEC 60444-9	NOTE	Harmonized as EN 60444-9.
IEC 61837-1	NOTE	Harmonized as EN 61837-1.
IEC 61837-2	NOTE	Harmonized as EN 61837-2.
IEC 61837-3	NOTE	Harmonized as EN 61837-3.
IEC 61837	NOTE	Harmonized in EN 61837 series.

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60444-5	-	Measurement of quartz crystal unit parameters - Part 5: Methods for the determination of equivalent electrical parameters using automatic network analyzer techniques and error correction	EN 60444-5	-

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INTERNATIONAL STANDARD



**Measurement of quartz crystal unit parameters –
Part 8: Test fixture for surface mounted quartz crystal units**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

MEASUREMENT OF QUARTZ CRYSTAL UNIT PARAMETERS –**Part 8: Test fixture for surface mounted quartz crystal units**

FOREWORD

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International Standard IEC 60444-8 has been prepared by IEC technical committee 49: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection.

This second edition cancels and replaces the first edition published in 2003. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) modification of Clause 1;
- b) modification of 5.2;
- c) modification of 5.3;
- d) modification of 5.4;

e) 6.3 Calibration of the reflection measurement system.

The text of this standard is based on the following documents:

CDV	Report on voting
49/1126/CDV	49/1175/RVC

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 60444 series, published under the general title *Measurement of quartz crystal unit parameters*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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A bilingual version of this publication may be issued at a later date.

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IMPORTANT – The colour inside logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.

INTRODUCTION

This document focuses on test fixtures applied to leadless surface mounted quartz crystal units. The document is the specification for fixtures [1][2]¹ that allow the measurement of (series) resonance frequency, (series) resonance resistance, and equivalent electrical circuit parameters of leadless surface mounted quartz crystal units. The measurement method using an automatic network analyzer with error correction is described in IEC 60444-5, which also contains proposals for test fixtures for quartz crystal units in through-hole packages.

The measuring frequency range is from 1 MHz to 1 200 MHz, and is limited to 1 MHz to 30 MHz, if a physical load capacitance is used. The use of the test fixtures in connection with error correction measurement techniques yields measurement accuracy of about 10^{-6} over of the frequency range, and the accuracy of the resonance resistance is $\pm 2 \Omega$ or $\pm 10 \%$.

This document forms Part 8 of a series of publications dealing with measurements of quartz crystal unit parameters.

The IEC 60444 series consists of the following parts under the general title *Measurement of quartz crystal unit parameters*:

- Part 1: Basic method for the measurement of resonance frequency and resonance resistance of quartz crystal units by zero phase technique in a π -network
- Part 2: Phase offset method for measurement of motional capacitance of quartz crystal units
- Part 4: Method for the measurement of the load resonance frequency f_L , load resonance resistance R_L and the calculation of other derived values of quartz crystal units, up to 30 MHz
- Part 5: Methods for the determination of equivalent electrical parameters using automatic network analyzer techniques and error correction
- Part 6: Measurement of drive level dependence (DLD)
- Part 7: Measurement of activity and frequency dips of quartz crystal units
- Part 8 Text fixture for surface mounted quartz crystal units
- Part 11 Standard method for the determination of the load resonance frequency f_L and the effective load capacitance C_{Leff} using automatic network analyzer techniques and error correction.

¹ Numbers in square brackets refer to the Bibliography.